

isc N-Channel MOSFET Transistor

IPW65R080CFD

IIPW65R080CFD

• FEATURES

- Static drain-source on-resistance:
 $R_{DS(on)} \leq 80m\Omega$
- Enhancement mode:
- 100% avalanche tested
- Minimum Lot-to-Lot variations for robust device performance and reliable operation

• DESCRIPTION

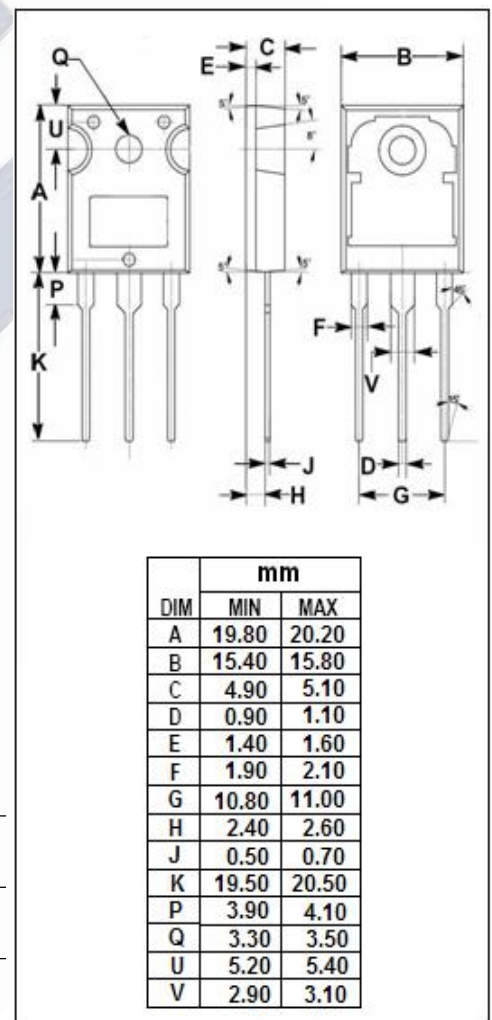
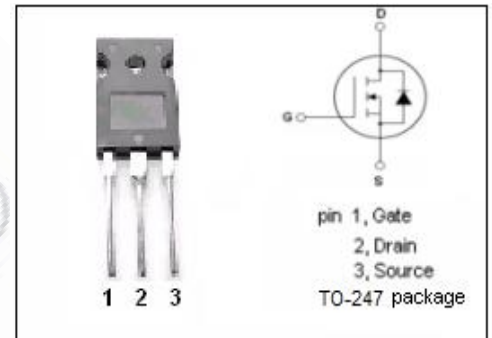
- Fast Switching

• ABSOLUTE MAXIMUM RATINGS($T_a=25^\circ C$)

SYMBOL	PARAMETER	VALUE	UNIT
V_{DS}	Drain-Source Voltage	650	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Drain Current-Continuous	43.3	A
I_{DM}	Drain Current-Single Pulsed	137	A
P_D	Total Dissipation @ $T_c=25^\circ C$	391	W
T_j	Max. Operating Junction Temperature	150	$^\circ C$
T_{stg}	Storage Temperature	-55~150	$^\circ C$

• THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	MAX	UNIT
$R_{th(j-c)}$	Channel-to-case thermal resistance	0.32	$^\circ C/W$
$R_{th(j-a)}$	Channel-to-ambient thermal resistance	62	$^\circ C/W$



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ELECTRICAL CHARACTERISTICS

 $T_c=25^{\circ}\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V; I_D=1mA$	650			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}; I_D=1.8mA$	3.5		4.5	V
$R_{DS(on)}$	Drain-Source On-Resistance	$V_{GS}=10V; I_D=17.6A$			41	$m\Omega$
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=20V; V_{DS}=0V$			0.1	mA
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=650V; V_{GS}=0V$			2	μA
V_{SD}	Diode forward voltage	$I_F=26.3A, V_{GS}=0V$				V